

# RELIABILITY MONITOR

| PRODUCT | MONITOR DATE | DATE CODE | ASSEMBLY FACILITY | ASSEMBLY LOT NO | PROCESS TYPE | PACKAGE TYPE |
|---------|--------------|-----------|-------------------|-----------------|--------------|--------------|
| DS1210  | Oct-96       | 9623 C1   | ANAM, K.          | DN603154AAN     | 3.0μ OX/NI   | 16 SOIC      |

**STRESS/JOB NO.**

**READPOINT  
(Sample Size/No. of Fails)**

Preconditioning (P/C):  
HTC Vapor Phase  
P-18329

|                   |              |
|-------------------|--------------|
| <u>Electrical</u> | <u>Cum %</u> |
| 233/0             | 0.0%         |

Sonoscan  
P-18370

|                         |
|-------------------------|
| <u>Post Vapor Phase</u> |
| 2/0                     |

Infant / High Voltage Life  
125°C, 7.0 V.  
P-18371, P-18406

|              |               |             |                      |
|--------------|---------------|-------------|----------------------|
| <u>48 Hr</u> | <u>336 Hr</u> | <u>1KHr</u> | <u>*Failure Rate</u> |
| 231/0        | 77/0          | 77/0        | 30 Fits              |

\*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle  
-55°C to +125°C  
P-18407

|              |             |              |
|--------------|-------------|--------------|
| <u>300 ~</u> | <u>1K ~</u> | <u>Cum %</u> |
| 39/0         | 39/0        | 0.0%         |

Biased Moisture  
85°C/85% RH, 5.5 V.  
P-18408

|               |               |              |
|---------------|---------------|--------------|
| <u>274 Hr</u> | <u>959 Hr</u> | <u>Cum %</u> |
| 77/0          | 77/0          | 0.0%         |

Autoclave  
121°C/100% RH, 2 Atmos  
P-18409

|              |              |
|--------------|--------------|
| <u>96 Hr</u> | <u>Cum %</u> |
| 38/0         | 0.0%         |

**Failure Mode**

**Failure Analysis**